

10/588636

**PATENT COOPERATION TREATY**  
**U.S./PCT RECEIVING OFFICE**

Applicants:	Kazuyoshi Okawa, et al.
U.S. National Stage Application of International Application No.	PCT/JP2004/001805
International Filing Date:	February 18, 2004
Attorney Docket No.	NAA243
Title:	Semiconductor Device Test Apparatus and Method

August 4, 2006

Commissioner of Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**INFORMATION DISCLOSURE STATEMENT**

Sir:

Pursuant to the duty of disclosure set forth in 37 CFR § 1.56, Applicants respectfully submit the following information disclosure statement.

The disclosed references are:

US 6,345,004, issued Feb. 5, 2002, Omura, et al., filed Dec. 26, 2000.

US 6,243,307, issued June 5, 2001, Kawagoe., filed Dec. 13, 1999.

JP-11-213695, Japanese Patent Office, published August 6, 1999, with English translation.

JP-2002-216495, Japanese Patent Office, published August 2, 2002, with English translation.

Stallman, R., translated by Toru Takizawa, "GNU Emacs 19 Manual", Addison Wesley Publishers Japan Kabushiki Kaisha, 31 October, 1997 (31.10.97), pp. 337-338 (with its English translation).

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AP20 Rec'd PCT/PTO 04 AUG 2006

Applicants respectfully request that the Examiner initial the cited references shown on the enclosed form PTO-1449 and that the references be made of record in the present application.

Respectfully submitted,



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**Certificate of Mailing Under 37 CFR 1.10**

I certify that this Information Disclosure Statement and all enclosed materials are being deposited with the United States Postal Service on August 4, 2006 as "Express Mail," mailing label EV 539509583 US, in an envelope addressed to Mail Stop PCT, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

  
Jean C. Reed

Enc. PTO Form 1449  
Cited references (5)  
Return receipt postcard

Substitute Form PTO-1449  INFORMATION DISCLOSURE STATEMENT	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	DOCKET NAA243	S.N. <b>10/588636</b>
		APPLICANT Kazuyoshi Okawa, et al.	
		FILING DATE	GROUP

**U.S. PATENT DOCUMENTS**

*Exam. Initial	Cite No.	DOCUMENT NUMBER Number - Kind Code	PUBLICATION DATE	NAME OF PATENTEE OR APPLICANT	FILING DATE
		US 6,345,004	2-5-02	Omura, et al.	12-26-00
		US 6,243,307	6-5-01	Kawagoe	12-13-99
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**FOREIGN PATENT DOCUMENTS**

*Exam. Initial	Cite No.	DOCUMENT NUMBER Number - Kind Code	PUBLICATION DATE	NAME OF PATENTEE OR APPLICANT	TRANSLATION YES NO	
		JP-11-213695	8-6-99	JAPAN, with English translation		X
		JP-2002-216495	8-2-02	JAPAN, , with English translation		X

**NON-PATENT LITERATURE DOCUMENTS**

*Exam. Initial	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	TRANSLATION YES NO	
		Stallman, R., translated by Toru Takizawa, "GNU Emacs 19 Manual", Addison Wesley Publishers Japan Kabushiki Kaisha, 31 October, 1997 (31.10.97), pp. 337-338 (with its English translation).		

EXAMINER	DATE CONSIDERED
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EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP; draw line through citation if not in conformance and not considered. Include copy of this form with next communication with applicant.